# International TOR Rectifier

## **IRFI4905**

HEXFET® Power MOSFET

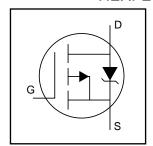
#### Advanced Process Technology

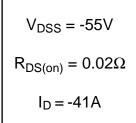
- Isolated Package
- High Voltage Isolation = 2.5KVRMS ⑤
- Sink to Lead Creepage Dist. = 4.8mm
- P-Channel
- Fully Avalanche Rated

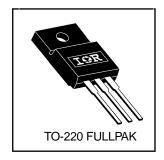
#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-41		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-29	A	
I <sub>DM</sub>	Pulsed Drain Current ①⑥	-260		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	63	W	
	Linear Derating Factor	0.42	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy@6	930	mJ	
I <sub>AR</sub>	Avalanche Current①⑥	-38	A	
E <sub>AR</sub>	Repetitive Avalanche Energy®	6.3	mJ	
dv/dt	Peak Diode Recovery dv/dt 36	-5.0	V/ns	
T <sub>J</sub>	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		2.4	0C ///
$R_{\theta JA}$	Junction-to-Ambient		65	°C/W

### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.05		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA ®
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.02	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -22A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
9 <sub>fs</sub>	Forward Transconductance	21			S	$V_{DS} = -25V, I_{D} = -38A$ ©
I	Drain-to-Source Leakage Current			-25		V <sub>DS</sub> = -55V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			-250	μA	$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
lass	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			180		$I_D = -38A$
Q <sub>gs</sub>	Gate-to-Source Charge			32	nC	$V_{DS} = -44V$
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			86		$V_{GS}$ = -10V, See Fig. 6 and 13 $\oplus$ $\textcircled{6}$
t <sub>d(on)</sub>	Turn-On Delay Time		18			$V_{DD} = -28V$
t <sub>r</sub>	Rise Time		99		ns	$I_{D} = -38A$
t <sub>d(off)</sub>	Turn-Off Delay Time		61		115	$R_G = 2.5\Omega$
t <sub>f</sub>	Fall Time		96			$R_D = 0.72\Omega$ , See Fig. 1046
1	Internal Drain Inductance		4.5		- nH	Between lead,
L <sub>D</sub>						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5			from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		3400			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		1400		pF	$V_{DS} = -25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		640	—		f = 1.0MHz, See Fig. 5 ©

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			11		MOSFET symbol
	(Body Diode)	-4	-41	A	showing the	
I <sub>SM</sub>	Pulsed Source Current			000		integral reverse
	(Body Diode) ①⑥	-260	-260		p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			-1.6	V	$T_J = 25^{\circ}C$ , $I_S = -22A$ , $V_{GS} = 0V$ ④
t <sub>rr</sub>	Reverse Recovery Time		89	130	ns	$T_J = 25$ °C, $I_F = -38A$
Q <sub>rr</sub>	Reverse RecoveryCharge		230	350	μC	di/dt = -100A/µs ④⑥
ton	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\label{eq:starting} \begin{array}{l} \text{ Starting T}_J = 25^{\circ}\text{C}, \ L = 1.3\text{mH} \\ \text{R}_G = 25\Omega, \ \text{I}_{AS} = \text{-38A}. \ \text{(See Figure 12)} \end{array}$
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- ⑤ t=60s, f=60Hz
- © Uses IRF4905 data and test conditions

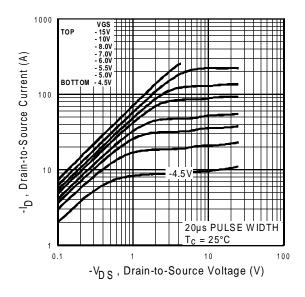


Fig 1. Typical Output Characteristics

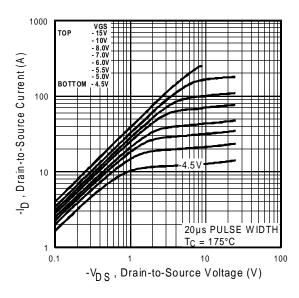


Fig 2. Typical Output Characteristics

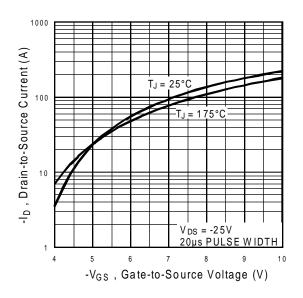
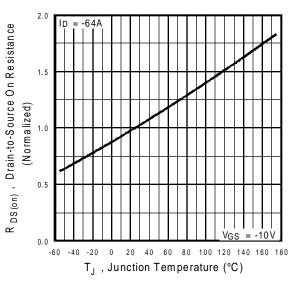
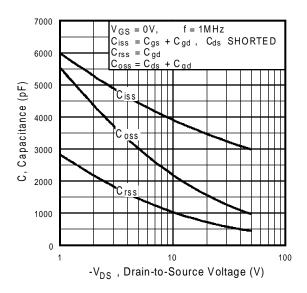


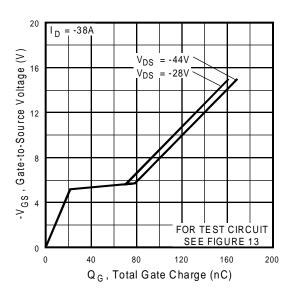
Fig 3. Typical Transfer Characteristics



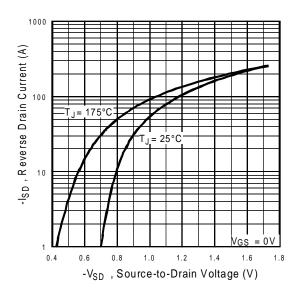
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage

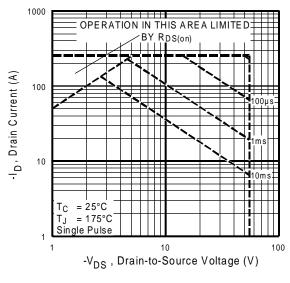
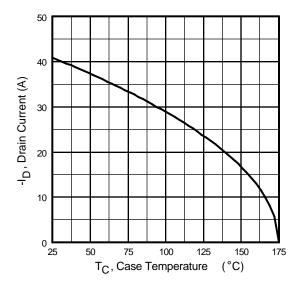


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

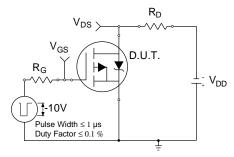


Fig 10a. Switching Time Test Circuit

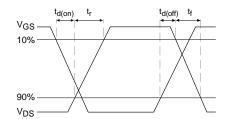


Fig 10b. Switching Time Waveforms

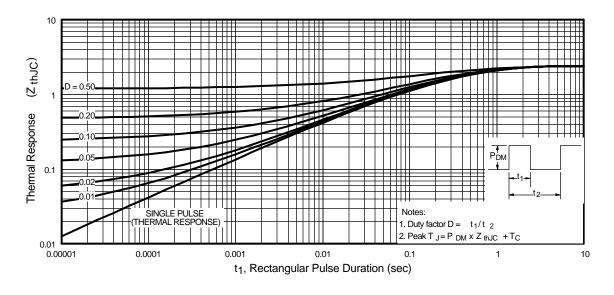


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

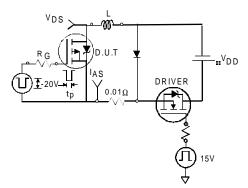


Fig 12a. Unclamped Inductive Test Circuit

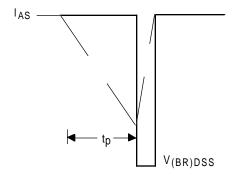


Fig 12b. Unclamped Inductive Waveforms

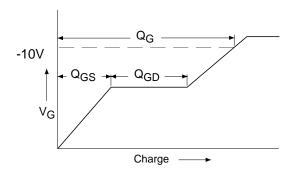
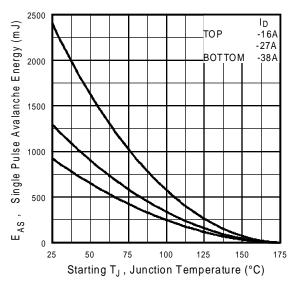


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

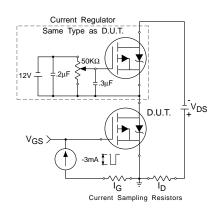
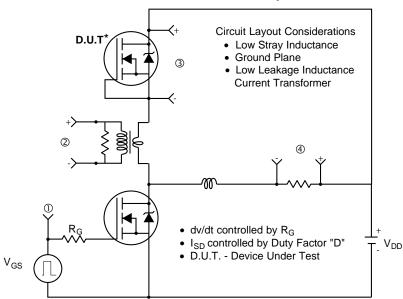
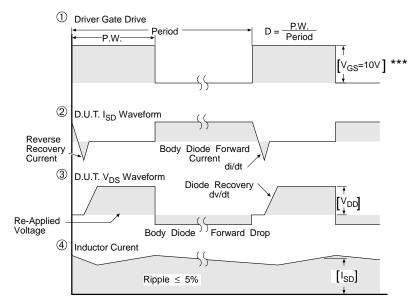


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



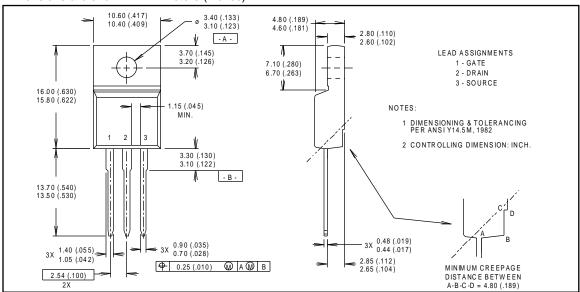
\*\*\*  $V_{GS} = 5.0V$  for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

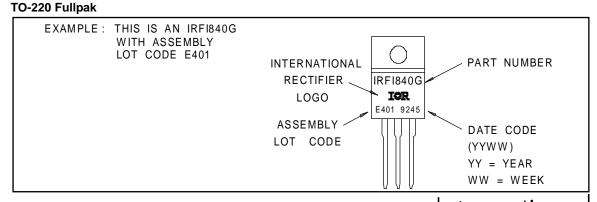
## Package Outline

#### **TO-220 Fullpak Outline**

Dimensions are shown in millimeters (inches)



## Part Marking Information



## International Rectifier

WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, Tel: (310) 322 3331 EUROPEAN HEADQUARTERS: Hurst Green, Oxted, Surrey RH8 9BB, UK Tel: ++ 44 1883 732020 IR CANADA: 7321 Victoria Park Ave., Suite 201, Markham, Ontario L3R 2Z8, Tel: (905) 475 1897 IR GERMANY: Saalburgstrasse 157, 61350 Bad Homburg Tel: ++ 49 6172 96590

IR ITALY: Via Liguria 49, 10071 Borgaro, Torino Tel: ++ 39 11 451 0111

IR FAR EAST: K&H Bldg., 2F, 30-4 Nishi-Ikebukuro 3-Chome, Toshima-Ku, Tokyo Japan 171 Tel: 81 3 3983 0086
IR SOUTHEAST ASIA: 315 Outram Road, #10-02 Tan Boon Liat Building, Singapore 0316 Tel: 65 221 8371
http://www.irf.com/ Data and specifications subject to change without notice. 8/97

Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>